Scanning Near Field Optical Microscopes probes-without tuning forks-wavelength 450-600nm

SNF_OMP-b

AFM Nanoprobes SNOM probes stand up to the most demanding applications, including infrared and UV/visible range. Our tips are made of high-quality polymers and also come in a variety of coatings to support your testing and imaging needs.Material – single mode optical fiber Nufern 460HP.
Probe tip is coated by Al (70nm)/sublayer V (20nm) .
Tip diameter uncoated by Al (tip aperture) 70 – 130 nm (100±30)
Angle of fiber – about 20 degrees
Maximum optical input power – 400 microWatt
The probes are prepared by chemical etching method.
This method gives the optical efficiency 102 – 104 times better than those obtained by mechanical pulling.GEOMETRICAL & MECHANICAL FIBER SPECIFICATIONS:SNOM PROBE CHARACTERISTICS:

SPECIFICATIONS

short_desc	SNOM probes (wavelength 450-600nm) for Scanning Near Field Optical Microscopes, without tuning forks
Quantity	10
Coating	Al Reflective
Cantilever	Single
Tip Material	Single mode optical fiber (Basic Nufern fiber)